

Notice of References Cited	Application/Control No. 10/566,828	Applicant(s)/Patent Under Reexamination TANAKA ET AL.
	Examiner Ryan Lepisto	Art Unit 2883

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0057868	05-2002	Wu et al.	385/24
*	B	US-4,569,569	02-1986	Stewart, William J.	385/36
*	C	US-2003/0081885	05-2003	Chen et al.	385/18
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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